


<b>Search Notes</b>  	<b>Application/Control No.</b>  10645099	<b>Applicant(s)/Patent Under Reexamination</b>  EDER, JEFF SCOTT
	<b>Examiner</b>  Susanna M Diaz	<b>Art Unit</b>  3692

SEARCHED			
Class	Subclass	Date	Examiner
705	1,10,35	3/1/09	SMD

SEARCH NOTES		
Search Notes	Date	Examiner
East (see attached)	3/1/09	SMD
Dialog (see attached)	3/1/09	SMD

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

--	--